Notice of References Cited Application/Control No. 10/708,642 Examiner Patricia A. George Applicant(s)/Patent Under Reexamination CHUANG ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*	_	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,809,790	10-2004	Yamagishi et al.	349/139
	В	US-2003/0122987	07-2003	Kim et al.	349/43
	Ċ	US-5,445,710	08-1995	Hori et al.	438/717
	D	US-5,354,417	10-1994	Cheung et al.	438/721
	E	US-2003/0143853	07-2003	Celii et al.	438/694
	F	US-4,904,980	02-1990	Przybysz et al.	338/307
	G	US-			
	Н	US-			
	1	UŞ-			
	J	US-			,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,
	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 05067590 A	03-1993	Japan	NAGATA et al.	H01L 21/302
	0					
	Þ					
	Q					
	R				·	
	s					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)						
	U	Wilson,1993, William Andrews/Noyes, Handbook of Multilevel metalization for Integrated Circuits - Materials, Technology, and Applications; pg 149-150						
	٧							
	w							
	х							

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.